Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	9880	(method and patterning semiconductor and reducing and (critical.adj dimension) and (feature or features) and (antireflective adj material)).clm.	US-PGPUB	OR	OFF	2005/11/09 11:43
L2	1	(method and patterning and semiconductor and reducing and (critical adj dimension) and (feature or features) and (antireflective adj material)).clm.	US-PGPUB	OR	OFF	2005/11/09 11:44